

Search Notes

Application/Control N .

10/621,372

Examiner

Dah-Wei D. Yuan

Applicant(s)/Patent und r
R examination

AKIYAMA ET AL.

Art Unit

1745

SEARCHED

| Class | Subclass | Date | Examiner |
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| 429 | 12 | 7/19/2006 | DWY |
| 429 | 34 | 7/19/2006 | DWY |
| 429 | 35 | 7/19/2006 | DWY |
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INTERFERENCE SEARCHED

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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
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